

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/512,100 | Applicant(s)/Patent Under Reexamination MELZER ET AL. | |
| | Examiner Loha Ben | Art Unit 2873 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,853,440 B1 | 02-2005 | Van De Pasch et al. | 355/53 |
| * | B | US-6,798,494 B2 | 09-2004 | Naulleau, Patrick P. | 355/67 |
| * | C | US-6,768,567 B2 | 07-2004 | Naulleau, Patrick P. | 359/15 |
| * | D | US-6,033,079 | 03-2000 | Hudyma, Russell | 359/857 |
| * | E | US-6,870,554 B2 | 03-2005 | Jain, Kanti | 345/697 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.